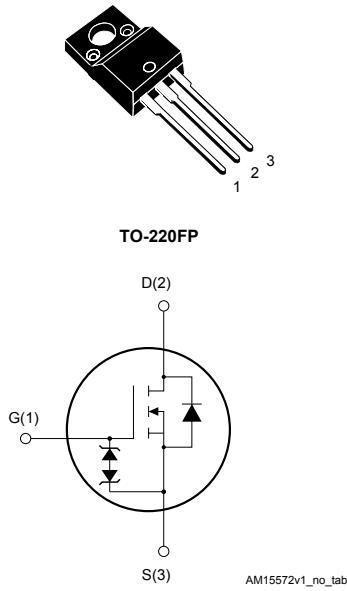


## N-channel 600 V, 230 mΩ typ., 13 A, MDmesh™ M6 Power MOSFET in a TO-220FP package

### Features



Order code	V <sub>DS</sub>	R <sub>DS(on)</sub> max.	I <sub>D</sub>
STF18N60M6	600 V	280 mΩ	13 A

- Reduced switching losses
- Lower R<sub>DS(on)</sub> per area vs previous generation
- Low gate input resistance
- 100% avalanche tested
- Zener-protected

### Applications

- Switching applications
- LLC converters
- Boost PFC converters

### Description

The new MDmesh™ M6 technology incorporates the most recent advancements to the well-known and consolidated MDmesh family of SJ MOSFETs. STMicroelectronics builds on the previous generation of MDmesh devices through its new M6 technology, which combines excellent R<sub>DS(on)</sub> per area improvement with one of the most effective switching behaviors available, as well as a user-friendly experience for maximum end-application efficiency.



#### Product status link

[STF18N60M6](#)

#### Product summary

Order code	STF18N60M6
Marking	18N60M6
Package	TO-220FP
Packing	Tube

## 1 Electrical ratings

**Table 1.** Absolute maximum ratings

Symbol	Parameter	Value	Unit
$V_{GS}$	Gate-source voltage	$\pm 25$	V
$I_D$	Drain current (continuous) at $T_{case} = 25^\circ C$	13	A
	Drain current (continuous) at $T_{case} = 100^\circ C$	8.2	
$I_{DM}^{(1)}$	Drain current (pulsed)	38	A
$P_{TOT}$	Total power dissipation at $T_{case} = 25^\circ C$	25	W
$dv/dt^{(2)}$	Peak diode recovery voltage slope	15	V/ns
$dv/dt^{(3)}$	MOSFET $dv/dt$ ruggedness	100	
$V_{ISO}$	Insulation withstand voltage (RMS) from all three leads to external heat sink ( $t = 1$ s; $T_{case} = 25^\circ C$ )	2.5	kV
$T_{stg}$	Storage temperature range	-55 to 150	°C
$T_j$	Operating junction temperature range		

1. Pulse width is limited by safe operating area.
2.  $I_{SD} \leq 13$  A,  $di/dt \leq 400$  A/ $\mu$ s,  $V_{DS(peak)} < V_{(BR)DSS}$ ,  $V_{DD} = 400$  V
3.  $V_{DS} \leq 480$  V

**Table 2.** Thermal data

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case	5	°C/W
$R_{thj-amb}$	Thermal resistance junction-ambient	62.5	°C/W

**Table 3.** Avalanche characteristics

Symbol	Parameter	Value	Unit
$I_{AR}$	Avalanche current, repetitive or non-repetitive (pulse width limited by $T_{Jmax}$ )	2.7	A
$E_{AS}$	Single pulse avalanche energy (starting $T_j = 25^\circ C$ , $I_D = I_{AR}$ , $V_{DD} = 50$ V)	210	mJ

## 2 Electrical characteristics

( $T_{case} = 25^\circ\text{C}$  unless otherwise specified).

**Table 4. On/off states**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	600			V
$I_{DSS}$	Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V}$			1	$\mu\text{A}$
		$V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V}, T_{case} = 125^\circ\text{C}^{(1)}$			100	
$I_{GSS}$	Gate-body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			$\pm 5$	$\mu\text{A}$
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	3.25	4	4.75	V
$R_{DSS(on)}$	Static drain-source on-resistance	$I_D = 6.5 \text{ A}, V_{GS} = 10 \text{ V}$		230	280	$\text{m}\Omega$

1. Defined by design, not subject to production test.

**Table 5. Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input capacitance	$V_{DS} = 100 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0 \text{ V}$	-	650	-	$\text{pF}$
$C_{oss}$	Output capacitance		-	45	-	
$C_{rss}$	Reverse transfer capacitance		-	2	-	
$C_{oss \text{ eq.}}^{(1)}$	Equivalent output capacitance	$V_{DS} = 0 \text{ to } 480 \text{ V}, V_{GS} = 0 \text{ V}$	-	123	-	pF
$R_G$	Intrinsic gate resistance	$f = 1 \text{ MHz}, I_D = 0 \text{ A}$	-	4.6	-	$\Omega$
$Q_g$	Total gate charge	$V_{DD} = 480 \text{ V}, I_D = 13 \text{ A}, V_{GS} = 0 \text{ to } 10 \text{ V}$ (see Figure 14. Test circuit for gate charge behavior)	-	16.8	-	$\text{nC}$
$Q_{gs}$	Gate-source charge		-	4.5	-	
$Q_{gd}$	Gate-drain charge		-	8.4	-	

1.  $C_{oss \text{ eq.}}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ .

**Table 6. Switching times**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 300 \text{ V}, I_D = 6.5 \text{ A}, R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see Figure 13. Test circuit for resistive load switching times and Figure 18. Switching time waveform)	-	16	-	ns
$t_r$	Rise time		-	7	-	
$t_{d(off)}$	Turn-off delay time		-	28	-	
$t_f$	Fall time		-	9	-	

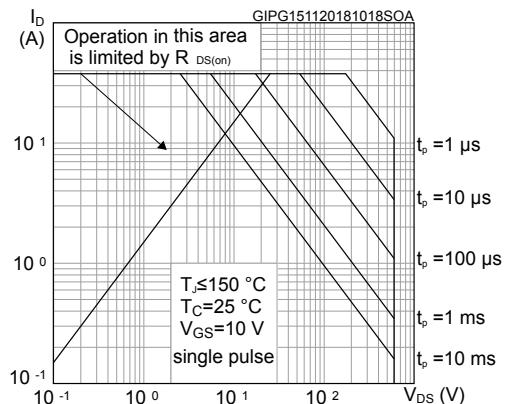
**Table 7. Source-drain diode**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}$	Source-drain current		-		13	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		38	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 13 \text{ A}, V_{GS} = 0 \text{ V}$	-		1.6	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 13 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s},$ $V_{DD} = 60 \text{ V}$	-	208		ns
$Q_{rr}$	Reverse recovery charge	(see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	1.9		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	18		A
$t_{rr}$	Reverse recovery time	$I_{SD} = 13 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s},$ $V_{DD} = 60 \text{ V}, T_j = 150^\circ\text{C}$	-	290		ns
$Q_{rr}$	Reverse recovery charge	(see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	2.9		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	20		A

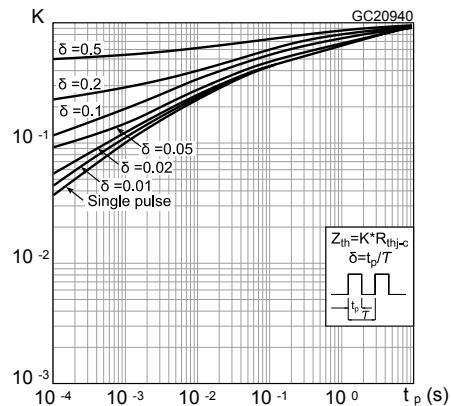
1. Pulse width is limited by safe operating area.
2. Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%

## 2.1 Electrical characteristics (curves)

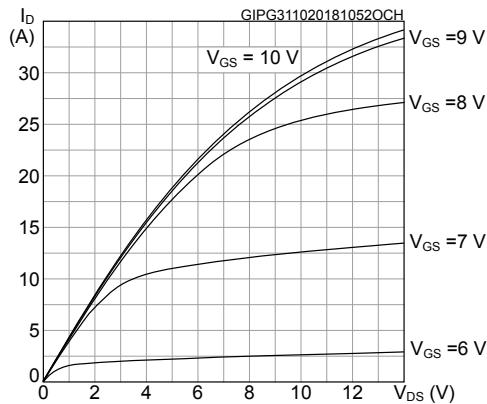
**Figure 1. Safe operating area**



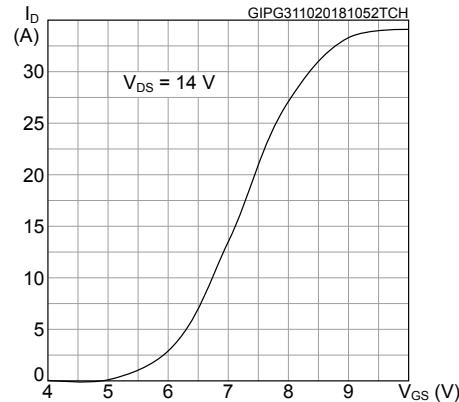
**Figure 2. Thermal impedance**



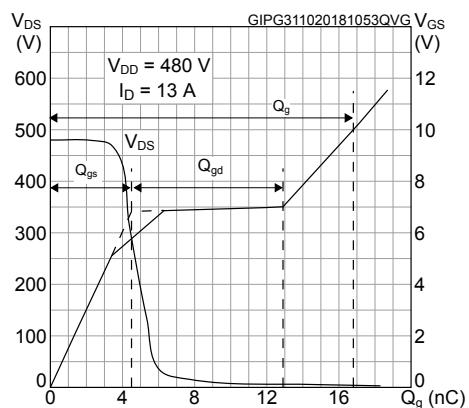
**Figure 3. Output characteristics**



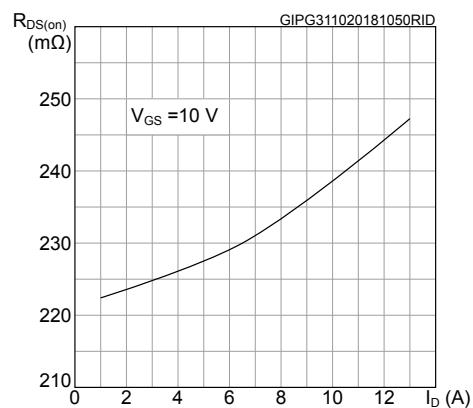
**Figure 4. Transfer characteristics**

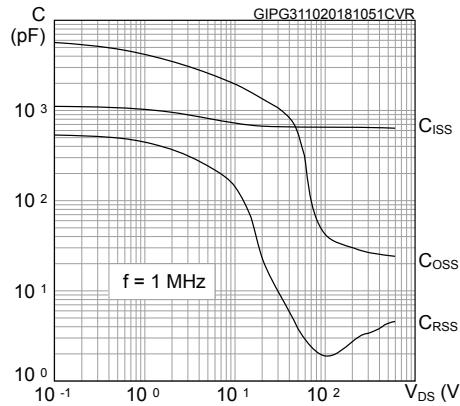
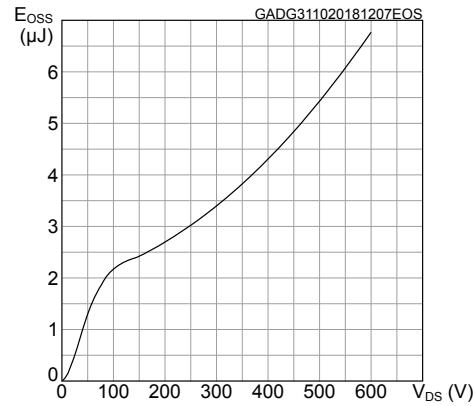
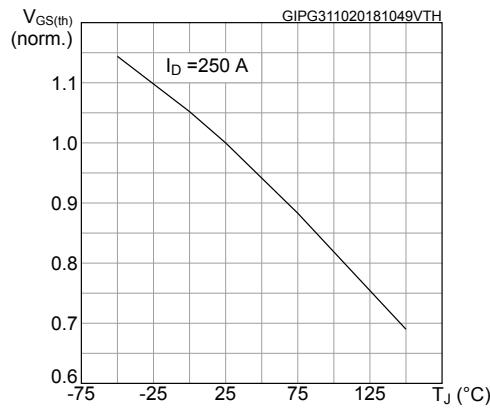
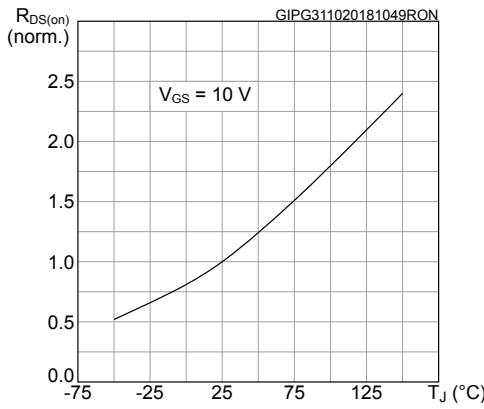
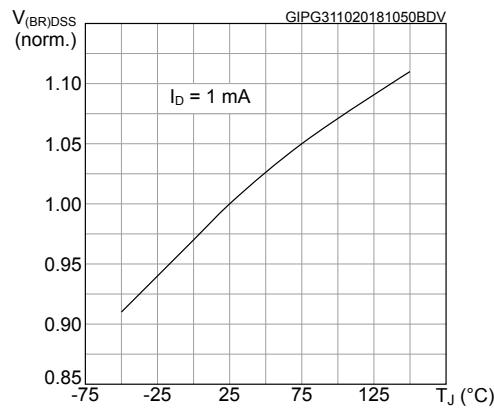
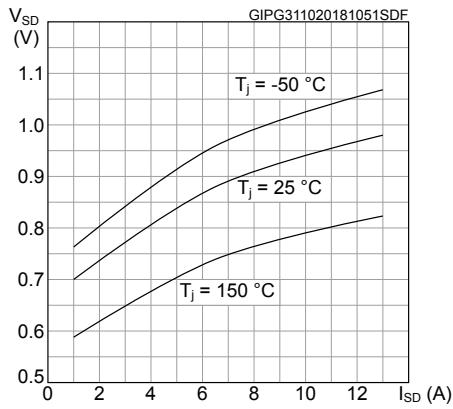


**Figure 5. Gate charge vs gate-source voltage**



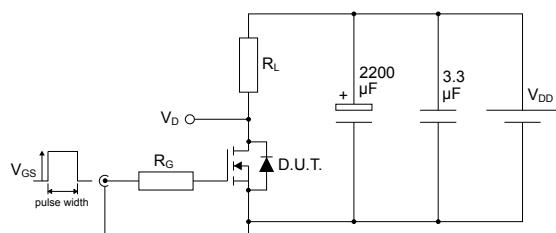
**Figure 6. Static drain-source on-resistance**



**Figure 7. Capacitance variations**

**Figure 8. Output capacitance stored energy**

**Figure 9. Normalized gate threshold voltage vs temperature**

**Figure 10. Normalized on-resistance vs temperature**

**Figure 11. Normalized V\_(BR)DSS vs temperature**

**Figure 12. Source-drain diode forward characteristics**


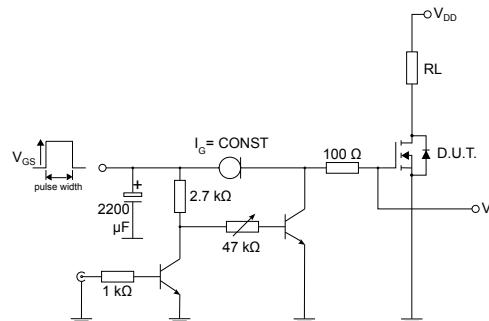
### 3 Test circuits

**Figure 13.** Test circuit for resistive load switching times



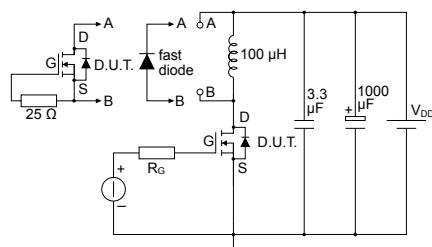
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**Figure 14.** Test circuit for gate charge behavior



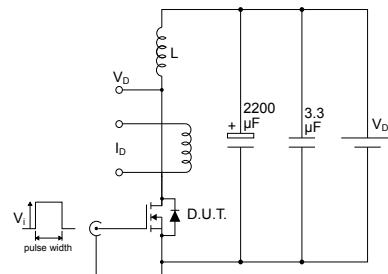
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**Figure 15.** Test circuit for inductive load switching and diode recovery times



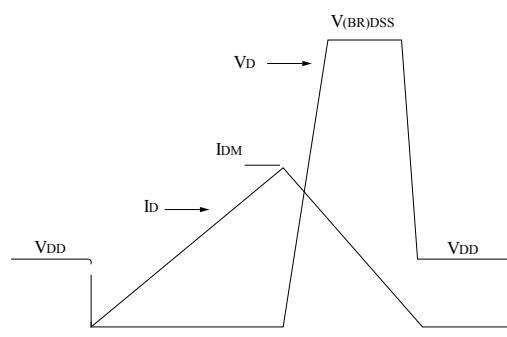
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**Figure 16.** Unclamped inductive load test circuit



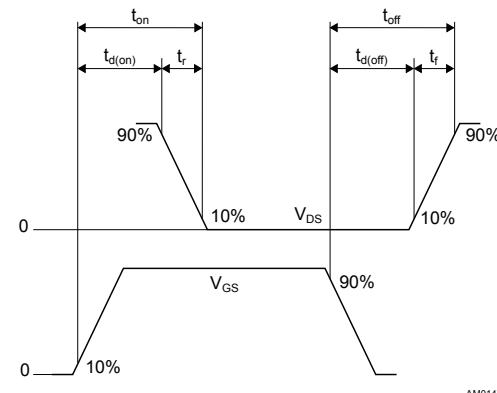
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**Figure 17.** Unclamped inductive waveform



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**Figure 18.** Switching time waveform



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**4**

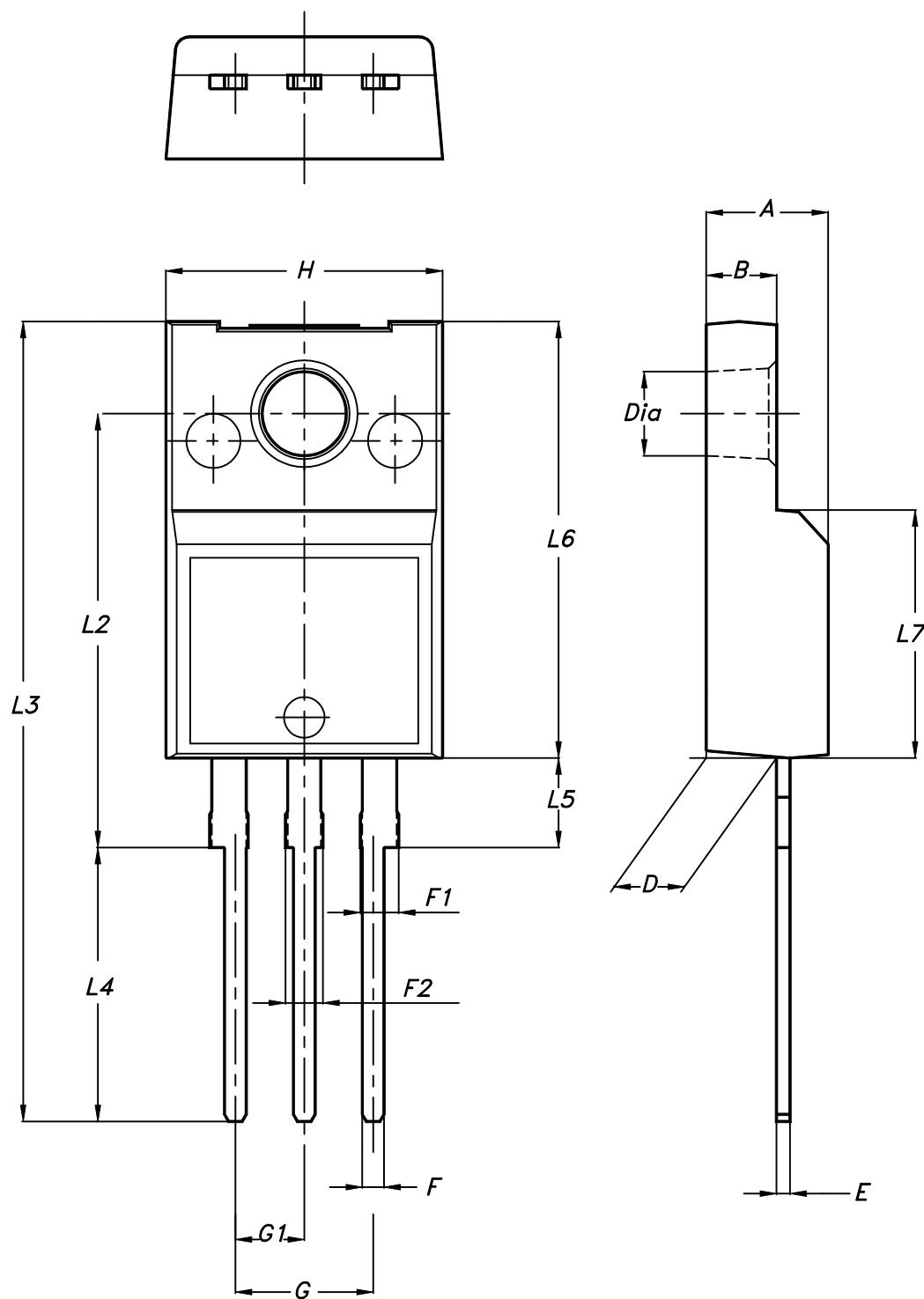
## Package information

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In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com). ECOPACK® is an ST trademark.

## 4.1 TO-220FP package information

Figure 19. TO-220FP package outline



7012510\_Rev\_12\_B

**Table 8.** TO-220FP package mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.4		4.6
B	2.5		2.7
D	2.5		2.75
E	0.45		0.7
F	0.75		1
F1	1.15		1.70
F2	1.15		1.70
G	4.95		5.2
G1	2.4		2.7
H	10		10.4
L2		16	
L3	28.6		30.6
L4	9.8		10.6
L5	2.9		3.6
L6	15.9		16.4
L7	9		9.3
Dia	3		3.2

## Revision history

**Table 9. Document revision history**

Date	Version	Changes
15-Nov-2018	1	First release.

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